

Application No.	Applicant(s)
10/052,847	YEUNG ET AL.
Examiner	Art Unit
Jack P Nguyen	2152

SEARCHED					
Class	Subclass	Date	Examiner		
709	200-206; 219-226	2/25/2005	JN		
709	246	2/26/2005	JN		
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Perform inventor's search for double patenting	2/24/2005	JN
Review IDS and art cited by applicant	2/24/2005	JN
Review related art to applicant's cited art	2/24/2005	JN
Consulted with D. Dinh on claim interpretations	2/25/2005	JN
Search class 709 and subclasses	2/25/2005	JN
Search related class and subclasses	2/26/2005	JN